High Performance Memory Testing: Design Principles, Fault Modeling and Self-Test (Frontiers in Electronic Testing)

R. Dean Adams
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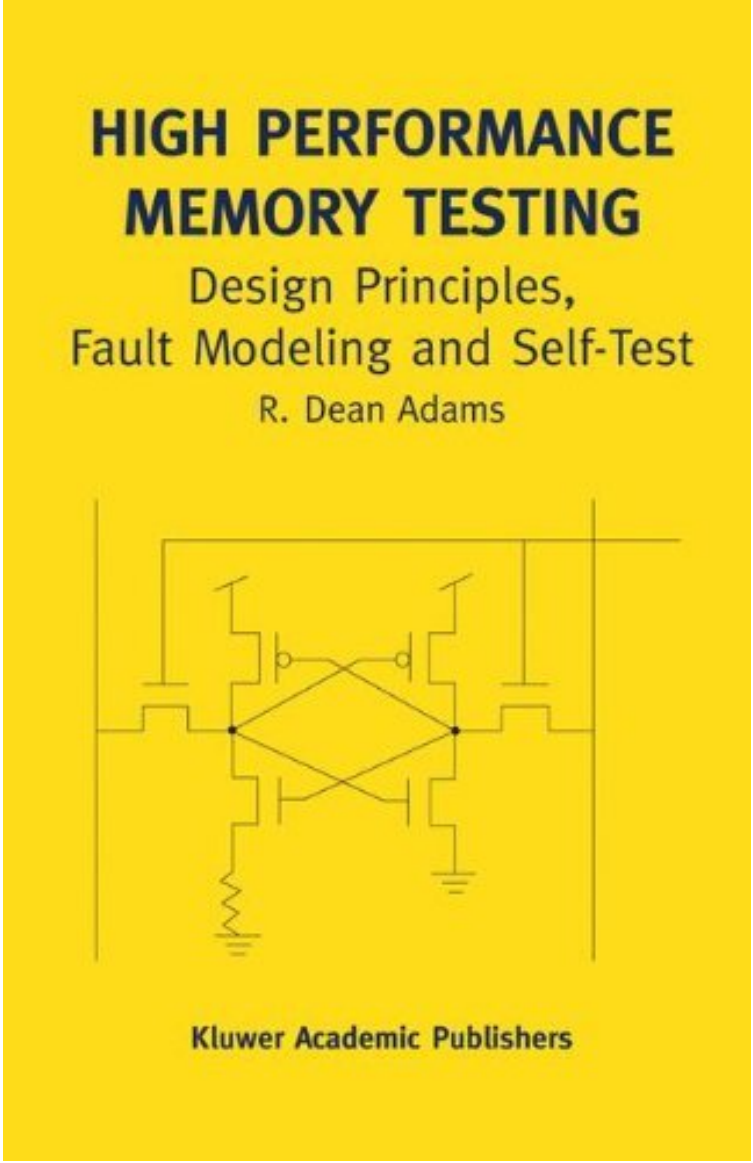

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R. Dean Adams : High Performance Memory Testing: Design Principles, Fault Modeling and Self-Test (Frontiers in Electronic Testing) before purchasing it in order to gage whether or not it would be worth my time, and all praised High Performance Memory Testing: Design Principles, Fault Modeling and Self-Test (Frontiers in Electronic Testing):

5 of 7 people found the following review helpful. A rare treatBy JTC____ In the world of semiconductor memory design, testing and diagnosis, information is scattered in papers, journals of various disciplines. Although text books are available, the coverage is often limited toacademic theories, models and algorithms. The more practical knowledge, unfortunately, have been mistakenly guarded as secret as a whole, although is often common knowledge for years among those in the field.____ The lack of reference text has always made it difficult for those who are less-experienced to break into the field. Having worked on memory diagnosis as a graduate student, consultant, and independent consultant, I remember the frustration. I often heard others in the field echoing the same frustration.____ Dean Adams has gathered those practical knowledges that in the past, can only be learned by years of experience into his book.

Are memory applications more critical than they have been in the past? Yes, but even more critical is the number of designs and the sheer number of bits on each design. It is assured that catastrophes, which were avoided in the past because memories were small, will easily occur if the design and test engineers do not do their jobs very carefully. High Performance Memory Testing: Design Principles, Fault Modeling and Self Test is based on the author's 20 years of experience in memory design, memory reliability development and memory self test. High Performance Memory Testing: Design Principles, Fault Modeling and Self Test is written for the professional and the researcher to help them understand the memories that are being tested.

From the reviews: "Fulfilling a need in the industry and a need in the literature, the book is certain to stimulate a heightened research interest in memory test, memory design, and memory elf test, each of which by itself constitutes an intriguing subject. The observations and approaches of the book make it a most useful work for the professional and the researcher in helping them understand the memories that are being tested." (Current Engineering Practice, Vol. 47, 2002-2003)